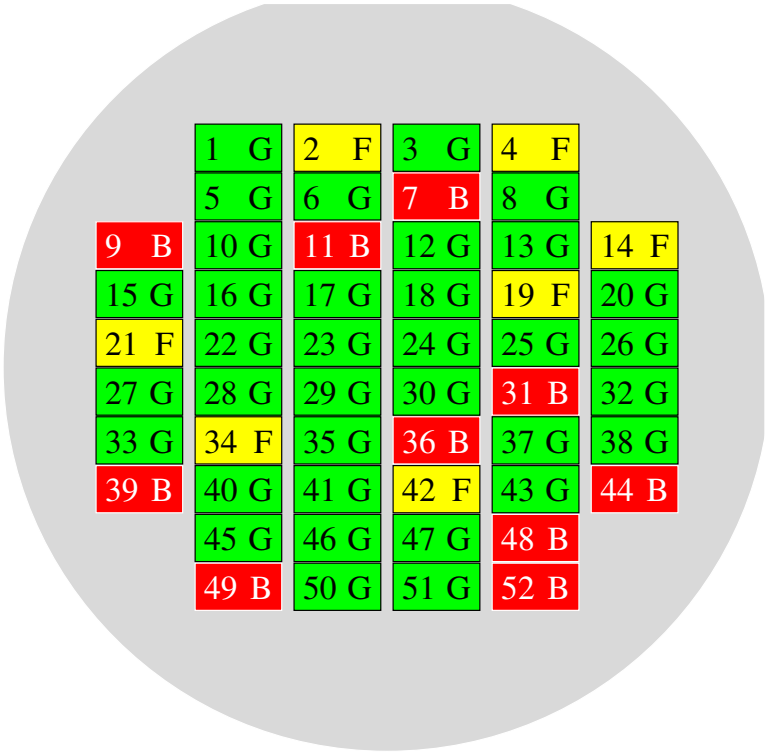
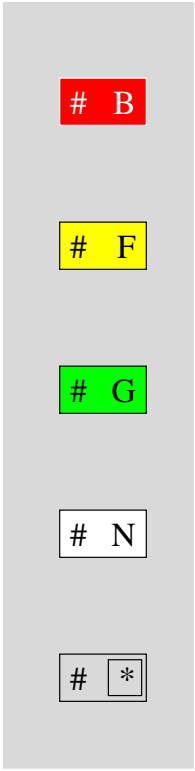
Die quality map for wafer 67 s/n: 21316-07-16

Date: 01/19/99





Bad die

Fair die

Good die

No info

Manually tagged